



UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE
United States Patent and Trademark Office
Address: COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, Virginia 22313-1450
www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
-----------------	-------------	----------------------	---------------------	------------------

10/645,665

08/22/2003

Raj Dhindsa

2328-062

8414

22429 7590 03/06/2007
LOWE HAUPTMAN BERNER, LLP
1700 DIAGONAL ROAD
SUITE 300
ALEXANDRIA, VA 22314

EXAMINER

LE, TUNG X

ART UNIT

PAPER NUMBER

2821

SHORTENED STATUTORY PERIOD OF RESPONSE	MAIL DATE	DELIVERY MODE
--	-----------	---------------

3 MONTHS

03/06/2007

PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

If NO period for reply is specified above, the maximum statutory period will apply and will expire 6 MONTHS from the mailing date of this communication.

Office Action Summary	Application No.		Applicant(s)	
	10/645,665		DHINDSA ET AL.	
	Examiner		Art Unit	
	Tung X. Le		2821	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on the Applicant's amendment 12/26/2006.
- 2a) ☒ This action is **FINAL**. 2b) ☐ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 15-23,25-51 and 64-79 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☒ Claim(s) 42-51 is/are allowed.
- 6) ☒ Claim(s) 15-23,25-33,35-37,39-41 and 64-79 is/are rejected.
- 7) ☒ Claim(s) 34,38 is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some * c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413) |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | Paper No(s)/Mail Date. _____ |
| 3) <input checked="" type="checkbox"/> Information Disclosure Statement(s) (PTO/SB/08) | 5) <input type="checkbox"/> Notice of Informal Patent Application |
| Paper No(s)/Mail Date <u>12/26/2006</u> . | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

1. This **final office action** is a response to the Applicant's amendment submitted on December 26, 2006. In virtue of this amendment:

- Claims 1-14, 24, and 52-63 are cancelled.
- Claims 69-79 are newly added; and
- Thus, claims 15-23, 25-51, and 69-79 are currently presented in the instant application.

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

3. Claims 15-23, 25-33, 35-37, and 39-41^{and 66-67} are rejected under 35 U.S.C. 102(e) as being anticipated by Vahedi et al. (U.S. 2004/0000875 A1).

With respect to claim 15, Vahedi discloses in figure 1 an apparatus for processing a workpiece (16 and 20) with a plasma (22) comprising a vacuum chamber (10) for processing the workpiece with the plasma (paragraph [0034]), and an electric source arrangement (70) for exciting the plasma with electric energy at three or more frequencies (paragraph [0025] shows the circuitry [70] simultaneously supplies power at

plural frequencies or three or more frequencies to the first electrode) such that the excitation of the plasma by the three or more frequencies simultaneously causes different phenomena to occur in the plasma (paragraphs [0025 and 0043]), wherein the phenomena affect plasma ion energy, plasma ion density and plasma chemistry of the plasma incident on the workpiece (paragraphs [0021 and 0043]).

With respect to claim 16, Vahedi discloses in figure 1 a vacuum plasma processor comprising a vacuum chamber (10) including an electrode (18 and 26), the chamber being associated with a reactance (76 and 78), the electrode and the reactance being arranged for coupling plasma excitation fields to gas (28) in the chamber (10), the chamber being arranged for carrying a workpiece (16 and 20) while the plasma excitation fields are coupled to the plasma (22), and a plasma excitation source arrangement (70) for enabling the electrode (18 and 26) and reactance (76 and 78) to couple the electric energy at three or more frequencies (paragraph [0025] shows the circuitry [70] simultaneously supplies power at **plural frequencies** or **three or more frequencies** to the first electrode) to the plasma (22) incident on the workpiece (16 and 20), the three or more frequencies being such that the excitation of the plasma by the three or more frequencies simultaneously causes different phenomena to occur in the plasma (paragraphs [0025 and 0043]), wherein the phenomena affect plasma ion energy, plasma ion density and plasma chemistry of the plasma incident on the workpiece (paragraphs [0021 and 0043]).

With respect to claim 17, Vahedi discloses that the plasma excitation source arrangement (70) is arranged for causing the three or more frequencies to be simultaneously applied to the plasma (figure 1, paragraphs [0025 and 0043]).

With respect to claim 18, Vahedi discloses in figure 1 that the electrode (18 and 26) for carrying the workpiece includes a first electrode (26) in the chamber and the reactance includes a second electrode (18) in the chamber (22).

With respect to claim 19, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) is arranged for applying a plurality of the frequencies (paragraph [0025]) to the first electrode (26) and at least one of the frequencies, that differs from the plurality of frequencies, to the second electrode (18).

With respect to claim 20, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) is arranged for applying three or more of the frequencies (paragraph [0025]) to the electrode (18 and 26).

With respect to claim 21, Vahedi discloses in figure 1 that the first and second electrodes (26 and 18) and the source arrangement (70) are arranged for causing the second electrode to be at a reference potential and for simultaneously causing the source arrangement to apply the three or more frequencies to the first electrode (paragraph [0043]).

With respect to claim 22, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) includes at least one variable frequency RF source (72 and 74).

With respect to claim 23, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) includes circuitry (76 and 78) for (a) providing an impedance match (figure 1) between sources (72 and 74) of the frequencies and the plasma (22) and (b) decoupling the frequencies (the variable frequencies from sources [72 and 74]) associated with the different sources (72 and 74) from each of the other sources (figure 1).

With respect to claim 25, Vahedi discloses in figure 1 a vacuum plasma processor for a workpiece (16 and 20) comprising a vacuum chamber (10) including first and second electrodes (18 and 26) for supplying plasma excitation fields to a region of the chamber adapted to be responsive to gas (28) adapted to be converted into a plasma (22) for processing the workpiece, the chamber being arranged for carrying the workpiece while the plasma exciting fields are supplied to the region, a plasma excitation source arrangement (70) for deriving electric energy at three or more frequencies (paragraph [0025] shows the circuitry [70] simultaneously supplies power at **plural frequencies or three or more frequencies** to the first electrode), the plasma excitation source arrangement (70) including circuitry (76 and 78) for selectively enabling coupling of the three or more frequencies (figure 1) to at least one of the first and second electrodes (18 and 26) for enabling plasma exciting electric fields at the three or more frequencies to be coupled to the plasma (figure 1).

With respect to claim 26, Vahedi discloses in figure 1 that the circuitry (76 and 78) is arranged for coupling a plurality of the frequencies (paragraph [0025]) to the first electrode (26) and for coupling at least one of the frequencies to the second electrode

Art Unit: 2821

(18), the at least one frequency being different from the plurality of frequencies (figure 1).

With respect to claim 27, Vahedi discloses in figure 1 that the circuitry is arranged for (a) providing an impedance match (76 and 78) between sources (72 and 74) of the frequencies and the plasma (22) and (b) decoupling the frequencies (the variable frequencies from sources [72 and 74]) associated with the different sources (72 and 74) from each of the other sources (figure 1).

With respect to claim 28, Vahedi discloses that the plasma excitation source arrangement (70) includes three or more different frequency sources (figure 1).

With respect to claim 29, Vahedi discloses that at least one of the sources (72 and 74) has a variable frequency (figure 1).

With respect to claim 30, Vahedi discloses that at least one of the sources (72 and 74) has a fixed frequency (figure 1).

With respect to claim 31, Vahedi discloses in figure 1 that various combinations of the three or more frequencies affect (a) the density of the plasma (b) the energy of ions in the plasma, and (c) the chemistry of the plasma (paragraphs [0012 and 0043]).

With respect to claim 32, Vahedi discloses that at least one of the sources has a variable output power (figure 1).

With respect to claim 33, Vahedi discloses in figure 1 that the circuitry and the chamber (22) are arranged for preventing substantial current to flow at least one of the plurality of frequencies (paragraph [0025]) to the second electrode (18).

With respect to claim 35, Vahedi discloses in figure 1 that the circuit is arranged for connecting the second electrode (18) to a reference potential and for supplying the three or more frequencies (paragraph [0025]) to the first electrode (26).

With respect to claim 36, Vahedi discloses that the circuitry is arranged for supplying the same frequency to the first and second electrode (figure 1).

With respect to claim 37, Vahedi discloses in figure 1 that the plasma source arrangement (70) is arranged for simultaneously coupling the three or more frequencies (paragraph [0025]) to the electrodes (18 and 26).

With respect to claim 39, Vahedi discloses that the controller (36) is arranged for selectively connecting the first electrode (26) to be responsive to each of the three or more frequencies (paragraph [0025]) during the first time period (figure 1)

With respect to claim 40, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) is arranged for applying three or more of the frequencies (paragraph [0025]) to the first electrode (26).

With respect to claim 41, Vahedi discloses that the first and second electrodes (18 and 26) and the source arrangement (70) are arranged for causing the second electrode to be at a reference potential and for simultaneously causing the source arrangement to apply the three or more frequencies to the first electrode (paragraph [0025 and 0043]).

With respect to claim 66, Vahedi discloses that the plasma excitation source arrangement (70) is arranged for simultaneously applying the first and second

Art Unit: 2821

frequencies to the first electrode (26) while applying the third frequency to the second electrode (figure 1).

With respect to claim 67, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) is arranged for simultaneously applying the first, second, and third frequencies to the first electrode (26) while the second electrode is at a reference potential (paragraphs [0025 and 0043]).

4. Claim 15 is rejected under 35 U.S.C. 102(b) as being anticipated by Donohoe et al. (U.S. 6,309,978 B1).

With respect to claim 15, Donohoe discloses in figures 1 and 5-6 an apparatus for processing a workpiece (column 9, lines 23-25) with a plasma (19, 106, 113) comprising a vacuum chamber (107) for processing the workpiece with the plasma (column 5, lines 39-58), and an electric source arrangement (figures 5-6) for exciting the plasma with electric energy at three or more frequencies (31-33 or 34-36) such that the excitation of the plasma by the three or more frequencies simultaneously causes different phenomena to occur in the plasma (column 6, lines 14-35), wherein the phenomena affect plasma ion energy, plasma ion density and plasma chemistry of the plasma incident on the workpiece (column 3, lines 35-47).

Claim Rejections - 35 USC § 103

5. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the

Art Unit: 2821

invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

6. Claims 64-65, 68, and 69-79 are rejected under 35 U.S.C. 103(a) as being unpatentable over Vahedi et al. (U.S. 2004/0000875 A1).

With respect to claims 64-65 and 68, Vahedi discloses all of the claimed subject matter, as expressly recited in claims 15, 16, and 25, except for specifying that the first, second, and third frequency is in the range of 100 kHz to 10 MHz, 10 MHz to 150 MHz, and 27 MHz to 300 MHz, respectively. However, such a difference of the three frequencies is not of patentable merits since the range of the frequencies of the power sources can be selected at a desired level based on a particular application or environment of use and such a selection would have been involved with only routine skills in the art. Therefore, to employ the different frequency ranges of the power sources of Vahedi at the first, second, and third frequency is in the range of 100 kHz to 10 MHz, 10 MHz to 150 MHz, and 27 MHz to 300 MHz, respectively, to be suitable to a desired application or environment of use would have been deemed obvious to a person skilled in the art.

With respect to claim 69, Vahedi discloses in figure 1 a vacuum plasma processor comprising a vacuum chamber (10) including an electrode (18 and 26), the chamber being associated with a reactance (76 and 78), the electrode and the reactance being arranged for coupling plasma excitation fields to gas (28) in the chamber (10), the chamber being arranged for carrying a workpiece (16 and 20) while the plasma excitation fields are coupled to the plasma (22), and a plasma excitation source arrangement (70) for enabling the electrode (18 and 26) and reactance (76 and

Art Unit: 2821

78) to couple the electric energy at three or more frequencies (paragraph [0025] shows the circuitry [70] simultaneously supplies power at **plural frequencies** or **three or more frequencies** to the first electrode) to the plasma (22) incident on the workpiece (16 and 20), except for specifying that the first, second, and third frequency is in the range of 100 kHz to 10 MHz, 10 MHz to 150 MHz, and 27 MHz to 300 MHz, respectively.

However, such a difference of the three frequencies is not of patentable merits since the range of the frequencies of the power sources can be selected at a desired level based on a particular application or environment of use and such a selection would have been involved with only routine skills in the art. Therefore, to employ the different frequency ranges of the power sources of Vahedi at the first, second, and third frequency is in the range of 100 kHz to 10 MHz, 10 MHz to 150 MHz, and 27 MHz to 300 MHz, respectively, to be suitable to a desired application or environment of use would have been deemed obvious to a person skilled in the art.

With respect to claim 70, Vahedi discloses that the plasma excitation source arrangement (70) is arranged for causing the three or more frequencies to be simultaneously applied to the plasma (figure 1, paragraphs [0025 and 0043]).

With respect to claim 71, Vahedi discloses in figure 1 that the electrode (18 and 26) for carrying the workpiece includes a first electrode (26) in the chamber and the reactance includes a second electrode (18) in the chamber (22).

With respect to claim 72, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) is arranged for simultaneously applying the first and second

Art Unit: 2821

frequencies to the first electrode (26) while applying the third frequency to the second electrode (18).

With respect to claim 73, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) is arranged for simultaneously applying the first, second, and third frequencies to the first electrode (26) while the second electrode is at a reference potential (paragraphs [0025 and 0043]).

With respect to claim 74, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) is arranged for applying a plurality of the frequencies (paragraph [0025]) to the first electrode (26) and at least one of the frequencies, that differs from the plurality of frequencies, to the second electrode (18).

With respect to claim 75, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) is arranged for applying three or more of the frequencies (paragraph [0025]) to the electrode (18 and 26).

With respect to claim 76, Vahedi discloses in figure 1 that the first and second electrodes (26 and 18) and the source arrangement (70) are arranged for causing the second electrode to be at a reference potential and for simultaneously causing the source arrangement to apply the three or more frequencies to the first electrode (paragraph [0043]).

With respect to claim 77, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) includes at least one variable frequency RF source (72 and 74).

With respect to claim 78, Vahedi discloses in figure 1 that the plasma excitation source arrangement (70) includes circuitry (76 and 78) for (a) providing an impedance match (figure 1) between sources (72 and 74) of the frequencies and the plasma (22) and (b) decoupling the frequencies (the variable frequencies from sources [72 and 74]) associated with the different sources (72 and 74) from each of the other sources (figure 1).

With respect to claim 79, Vahedi discloses in figure 1 that the excitation source arrangement (70) is arranged and the frequencies have values for causing three or more different phenomena to occur simultaneously in the plasma (paragraphs [0025 and 0043]).

Allowable Subject Matter

7. Claims 42-51 are allowed.
8. Claims 34 and 38 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.
9. The following is a statement of reasons for the indication of allowable subject matter:

Prior art of record fails to disclose or fairly suggest the following limitations:

- A vacuum plasma processor for a workpiece comprising a filter arrangement of the circuitry, the filter arrangement being connected to the second electrode for preventing the substantial flow of current at least one of the plurality of frequencies between the second electrode and the reference electrode, in

combination with the remaining claimed limitations as claimed in dependent claim 34.

- A vacuum plasma processor for a workpiece comprising a reference potential during a first workpiece processing time period and for selectively supplying the same frequency to the first and second electrodes during a second workpiece processing time period, in combination with the remaining claimed limitations as claimed in dependent claim 38.
- A vacuum plasma processor for processing a workpiece comprising the electrode arrangement including first and second electrodes respectively on opposite first and second sides of the region and a third electrode on the first side of the region, the third electrode being peripheral to and electrically insulated from the first electrode, a plasma excitation source arrangement for deriving electric energy at plural frequencies, the plasma excitation source arrangement being arranged for selectively coupling energy at the plural frequencies to the first, second and third electrodes for causing current at at least one of the plural frequencies to flow in the third electrode without current at all of the frequencies flowing in the third electrode, in combination with the remaining claimed limitations as claimed in claim 42 (claims 43-51 are allowed for depending on claim 42).

Response to Arguments

10. Applicant's arguments with respect to claims 15, 16, 25, and 69 have been considered but are moot in view of the new ground(s) of rejection.

Citation of Relevant Prior Art

11. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Hoffman et al. (U.S. 6,853,141 B2) discloses a capacitively coupled plasma reactor with magnetic plasma control.

Hoffman et al. (U.S. 2003/0062344 A1) discloses a plasma reactor with overhead RF electrode tuned to the plasma.

Inquiry

12. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

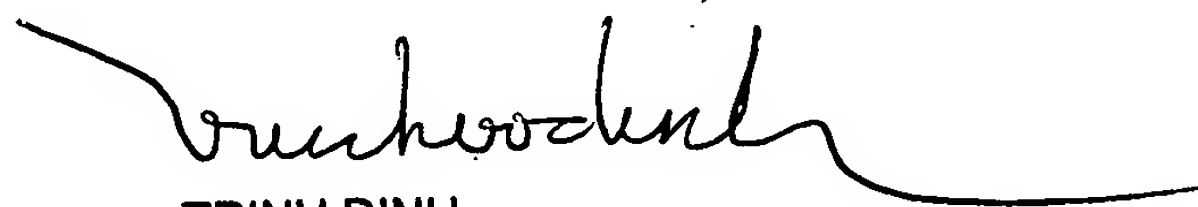
A shortened statutory period for reply to this final action is set to expire **THREE MONTHS** from the mailing date of this action. In the event a first reply is filed within **TWO MONTHS** of the mailing date of this final action and the advisory action is not mailed until after the end of the **THREE-MONTH** shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than **SIX MONTHS** from the date of this final action.

13. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tung X. Le whose telephone number is 571-272-6010. The examiner can normally be reached on 8:30 AM - 5:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Douglas Owens can be reached on 571-272-1662. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Examiner
Tung Le
AU 2821



TRINH DINH
PRIMARY EXAMINER

February 27, 2007